OIPE		
JUL 2 0 2006	Docket No.: 272537US0PCT	Serial No.: 10/538,920
LIST OF RELATED CASES CITED BY	Inventor: Xavier BLIN, et al.	
APPLICANT UNDER 37 CFR 1.56	Filing Date: December 12, 2005	Group: 1642
LIST O	F RELATED CASES	<u> </u>

Examiner <u>Initial</u>	Docket No.	Serial or Patent Number	Filing or Issue Date	Patent App. Publication No.	Inventor or Applicant	
	272537US0PCT*	10/538,920	12/12/05		BLIN, et al.	
	285142US0	11/342,748	01/31/06		BLIN, et al.	

Examiner /Caralynne Helm/ Date Considered

11/03/2008

^{*}Present Application; listed for information NFO/sbc

Form PTO 1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO. SERIAL NO.			1 - 1 - 1			
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LIST OF REFERENCES CITED BY APPLICANT & Xavier BLIN, et al.									
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		W. S. T.	ADEMASH ST	U.S. PATENT DOCUMENTS					
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME CLASS SUB CLASS IF APPROPRI					
	AA	5,512,272	04/30/96	Krzysik, D.					
	AB	6,682,748	01/27/04	De La Poterie, et al.					
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			FO	REIGN PATENT DOCUMENTS					
		DOCUMENT		-		-	TD 4110	471011	
		NUMBER	DATE	COUNTRY		YE	TRANS	NO NO	
	AQ	JP2001-081009	3/27/01	Japan (English Abstract Provided)	abst	ract		X	
	AP	JP09-071505	03/18/97	Japan (English Abstract Provided)	abst	ract	only	x	
	AQ	JP2001-503070	03/06/01	Japan (Corresponds to WO/9922710)				×	
	AP	W099/22710	05/14/99	WIPO (Corresponds to JP2001-503070)	×			
	AS	JP08-239316	10/04/94	Japan (Corresponds to EP 0 709083)				X	
	AT	EP 0 709083	05/01/96	EPO (Corresponds to JP 08-239316)		×			
	AU	JP11-236314	08/31/99	Japan (Corresponds to US 6,682,748)	abst	ract	only	×	
	-A-V-	JP02-25411	01/20/00	Japan (English Abstract Provided)					
	OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
							Translati	lan)	
	AW Notice of Rejection for Japanese Patent Application 2004-512707 issued June 6, 2006 (w/English Translation).								
	AX								
	AY								
	AZ				Addi	tional Ref	erences :	sheet(s) attached	
Examiner	Examiner /Caralynne Helm/ Date Considered 11/03/2008							03/2008	
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									

Note: reference AV had two of its numbers transposed, so the provided English abstract of JP2025411 was considered instead of the cited JP0225411

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